

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10800397	FLESCH ET AL.
Examiner	Art Unit	
Nano, Sargon N	2157	

### SEARCHED

Class	Subclass	Date	Examiner

### SEARCH NOTES

Search Notes	Date	Examiner
Consulted with Primary Yves Dalencourt	11/22/2008	SN

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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